

Features

- Uses CRM(CQ) advanced SkyMOS2 technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria
- Typical ESD (HBM): 400 V
- MSL1 rated

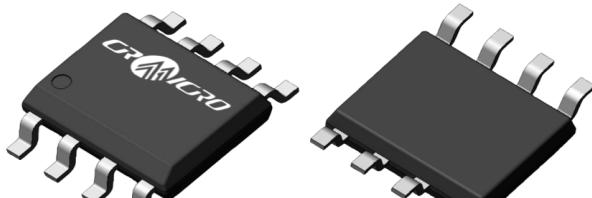
Product Summary

V_{DS}	100
$R_{DS(on)}@10V$ typ	11.0mΩ
$R_{DS(on)}@4.5V$ typ	14.0mΩ
I_D	11A

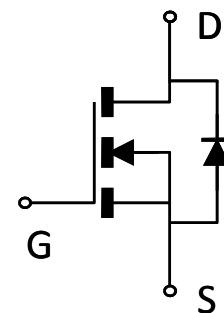
Applications

- Synchronous Rectification for AC/DC Quick Charger
- Battery management
- UPS (Uninterruptible Power Supplies)

100% Avalanche Tested



CRSE120N10L2X



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRSE120N10L2X	-	SOP-08	Tape&Reel	N/A	N/A	4000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	100	V
Continuous drain current $T_A = 25^\circ C$ $T_A = 75^\circ C$	I_D	11 8	A
Pulsed drain current ($T_A = 25^\circ C$, t_p limited by T_{jmax})	$I_{D\ pulse}$	44	A
Avalanche energy, single pulse ($L=0.1mH$, $R_g=25\Omega$)	E_{AS}	45	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_A = 25^\circ C$)	P_{tot}	2.8	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R _{thJC}	21.8	°C/W
Thermal resistance, junction – ambient(min. footprint)	R _{thJA}	45	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	100	115	-	V	V _{GS} =0V, I _D =250uA
Gate threshold voltage	V _{GS(th)}	1.4	1.8	2.2	V	V _{DS} =V _{GS} , I _D =250uA
Zero gate voltage drain current	I _{DSS}	-	0.05	1	μA	V _{DS} =100V, V _{GS} =0V T _j =25°C T _j =125°C
Gate-source leakage current	I _{GSS}	-	10	100	nA	V _{GS} =±20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	11.0	13.2	mΩ	V _{GS} =10V, I _D =11A
		-	14.0	17.5		V _{GS} =4.5V, I _D =11A
Transconductance	g _{fs}	-	38	-	S	V _{DS} =5V, I _D =11A

Dynamic Characteristic

Input Capacitance	C _{iss}	485.4	1618	2427	pF	V _{GS} =0V, V _{DS} =50V, f=1MHz
Output Capacitance	C _{oss}	83.1	277	470.9		
Reverse Transfer Capacitance	C _{rss}	6.6	22	44		
Gate Total Charge	Q _G	-	28.2	56.4	nC	V _{GS} =10V, V _{DS} =50V, I _D =11A, f=1MHz
Gate-Source charge	Q _{gs}	-	6.5	13		
Gate-Drain charge	Q _{gd}	-	4.5	9		
Turn-on delay time	t _{d(on)}	-	30	60	ns	V _{GS} =10V, V _{DD} =50V, R _{G_ext} =2.7Ω
Rise time	t _r	-	81	162		
Turn-off delay time	t _{d(off)}	-	24	48		
Fall time	t _f	-	7	14		
Gate resistance	R _G	-	1.62	3	Ω	V _{GS} =0V, V _{DS} =0V, f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V _{SD}	-	0.83	1	V	V _{GS} =0V, I _{SD} =11A
Body Diode Reverse Recovery Time	t _{rr}	-	78	132.6	ns	I _F =11A, dI/dt=100A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	-	192	326.4	nC	

Typical Performance Characteristics

Fig 1: Output Characteristics

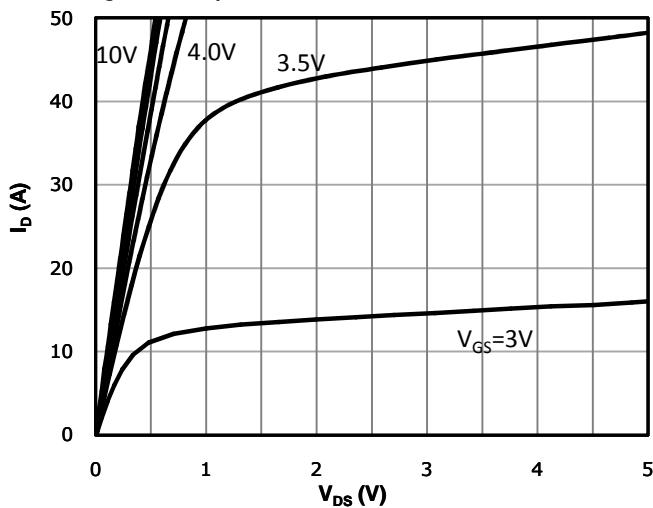


Fig 2: Transfer Characteristics

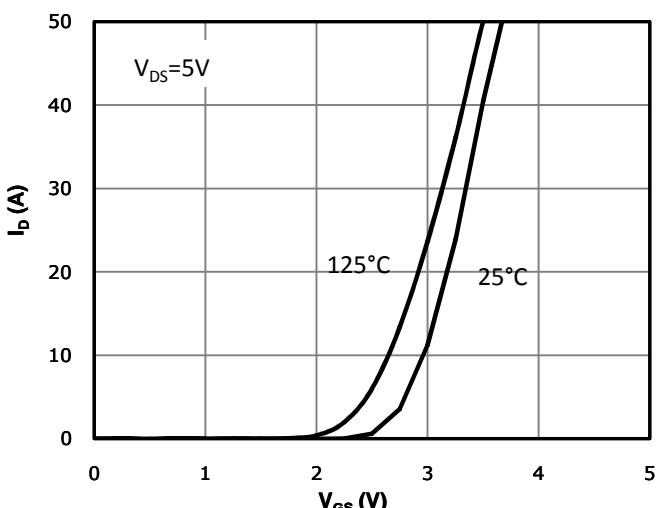


Fig 3: $R_{DS(on)}$ vs Drain Current and Gate Voltage

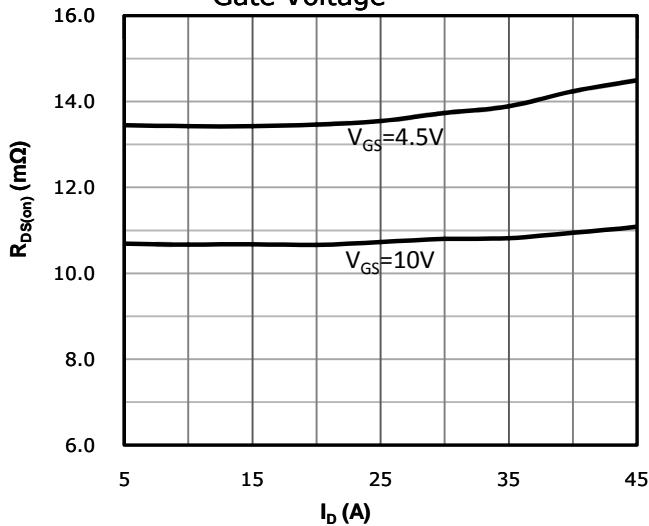


Fig 4: $R_{DS(on)}$ vs Gate Voltage

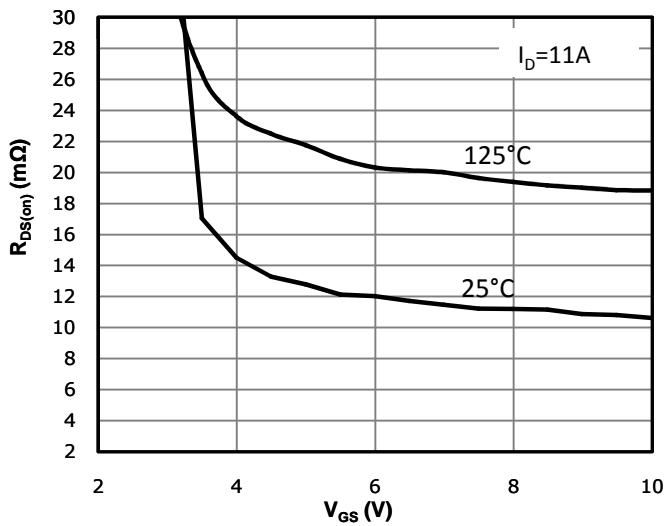


Fig 5: $R_{DS(on)}$ vs. Temperature

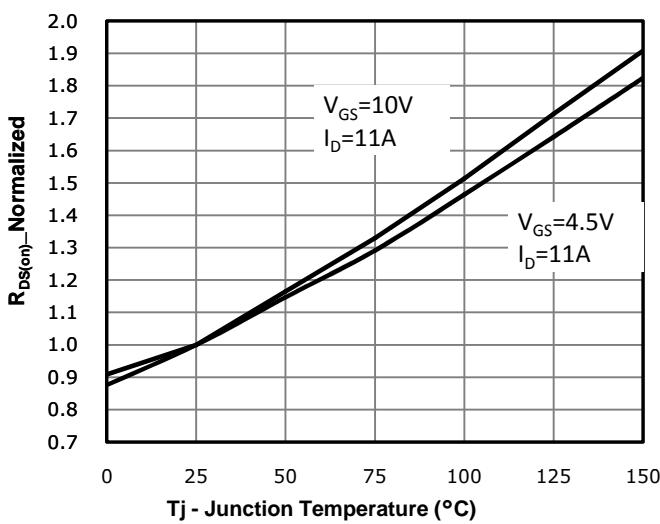


Fig 6: Capacitance Characteristics

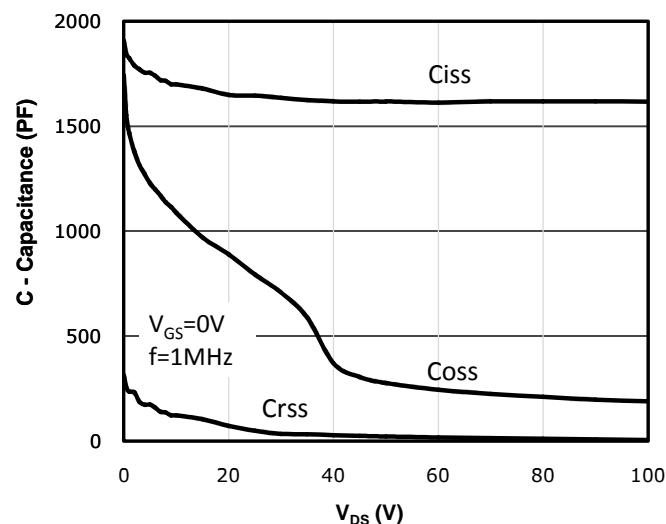


Fig 7: Gate Charge Characteristics

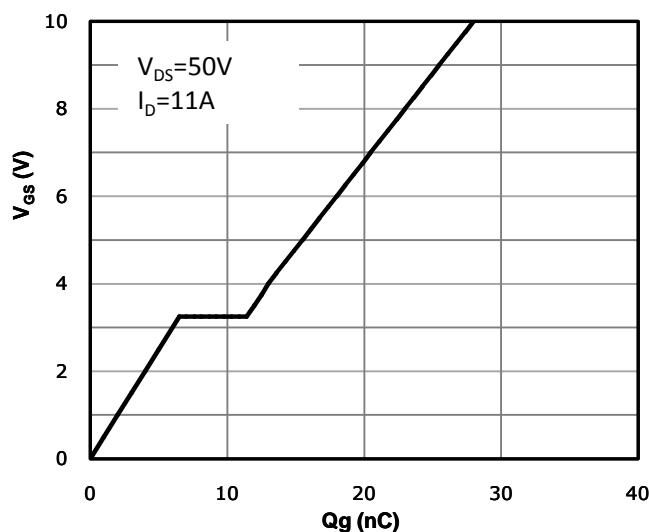


Fig 8: Body-diode Forward Characteristics

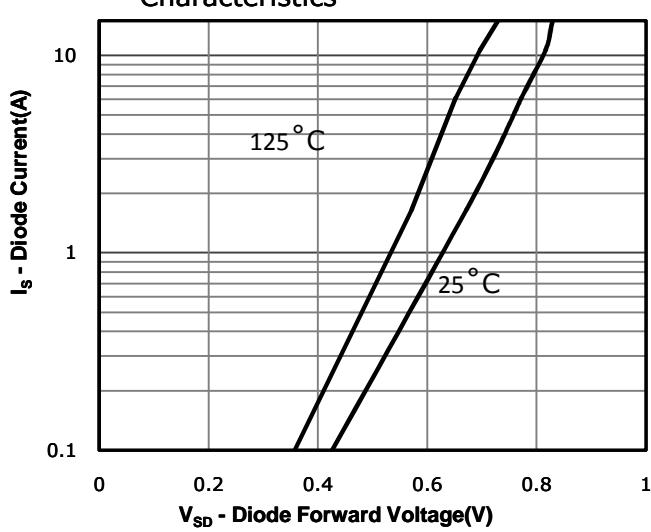


Fig 9: Power Dissipation

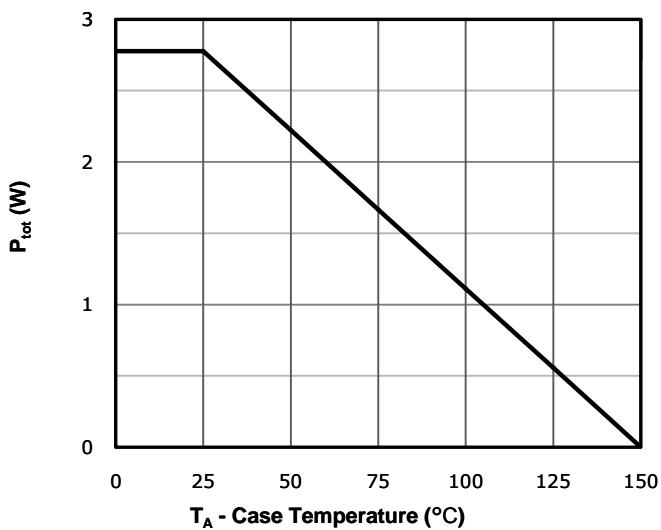


Fig 10: Drain Current Derating

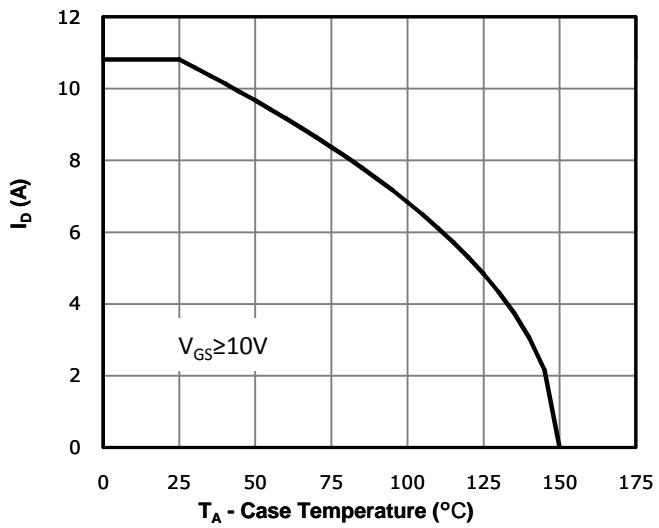


Fig 11: Safe Operating Area

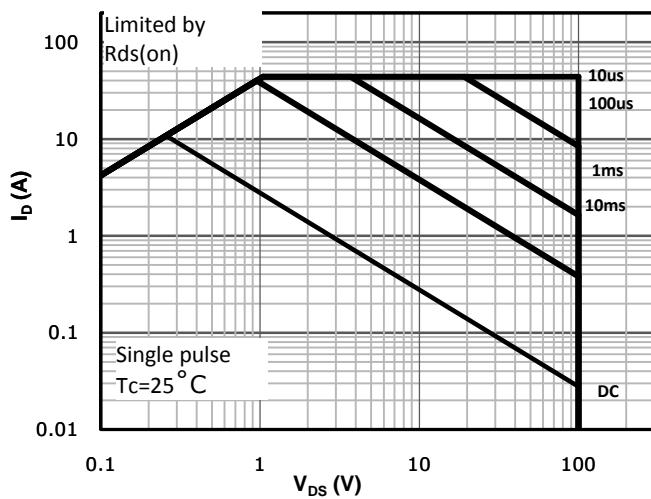
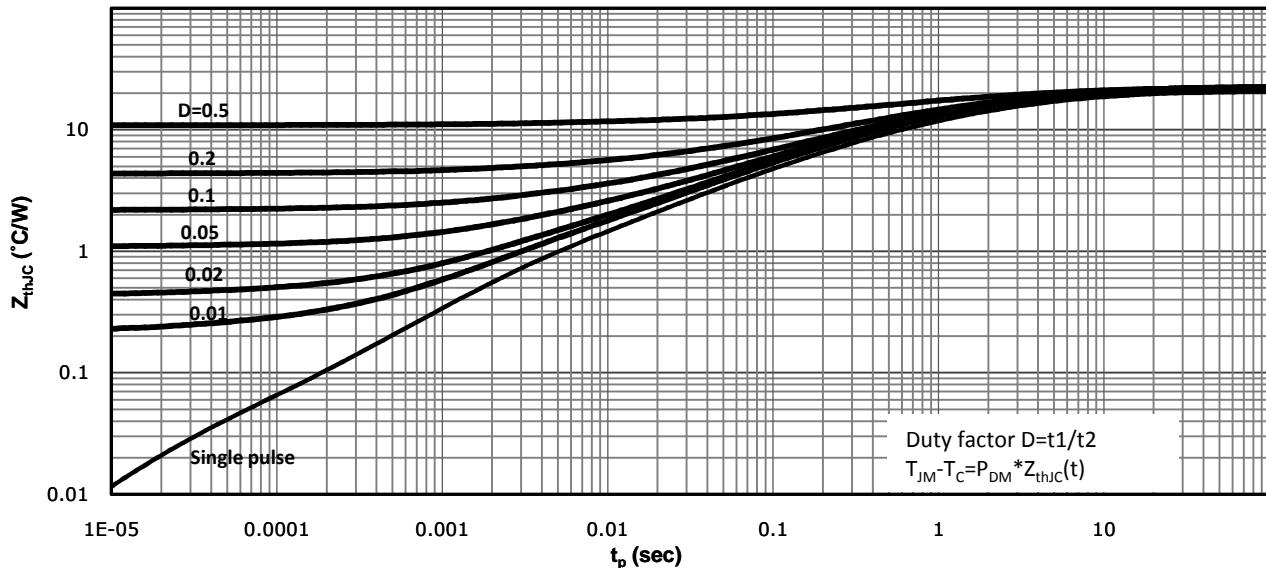
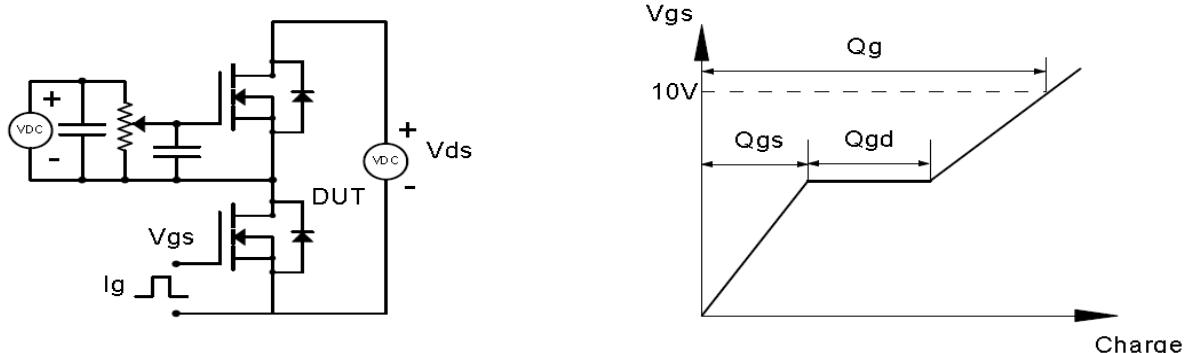


Fig 12: Max. Transient Thermal Impedance

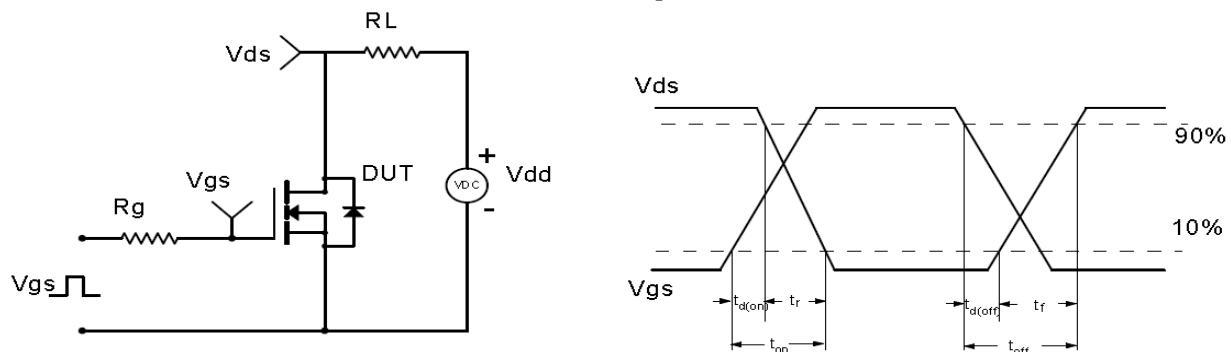


Test Circuit & Waveform

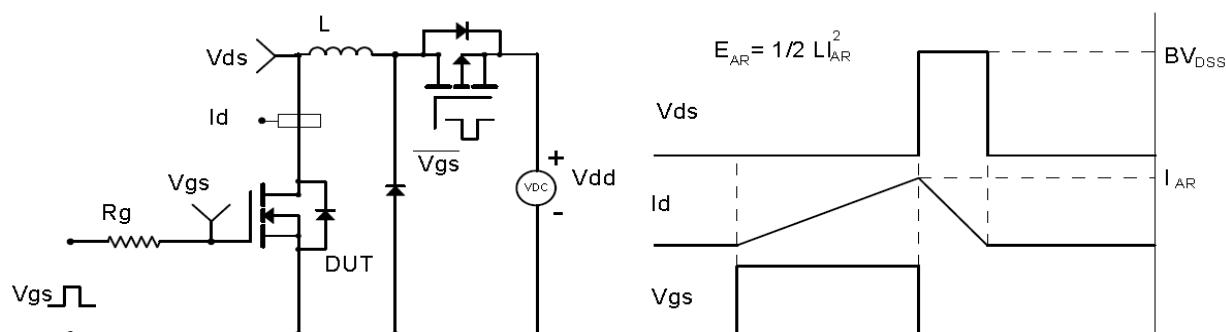
Gate Charge Test Circuit & Waveform



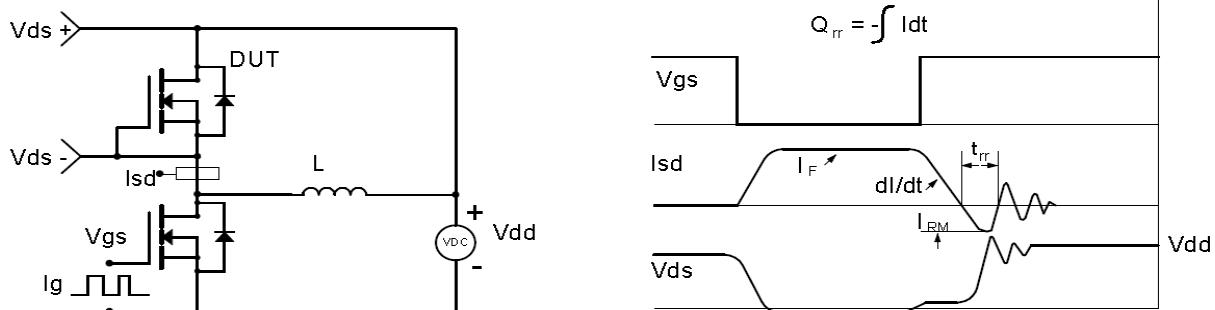
Resistive Switching Test Circuit & Waveforms

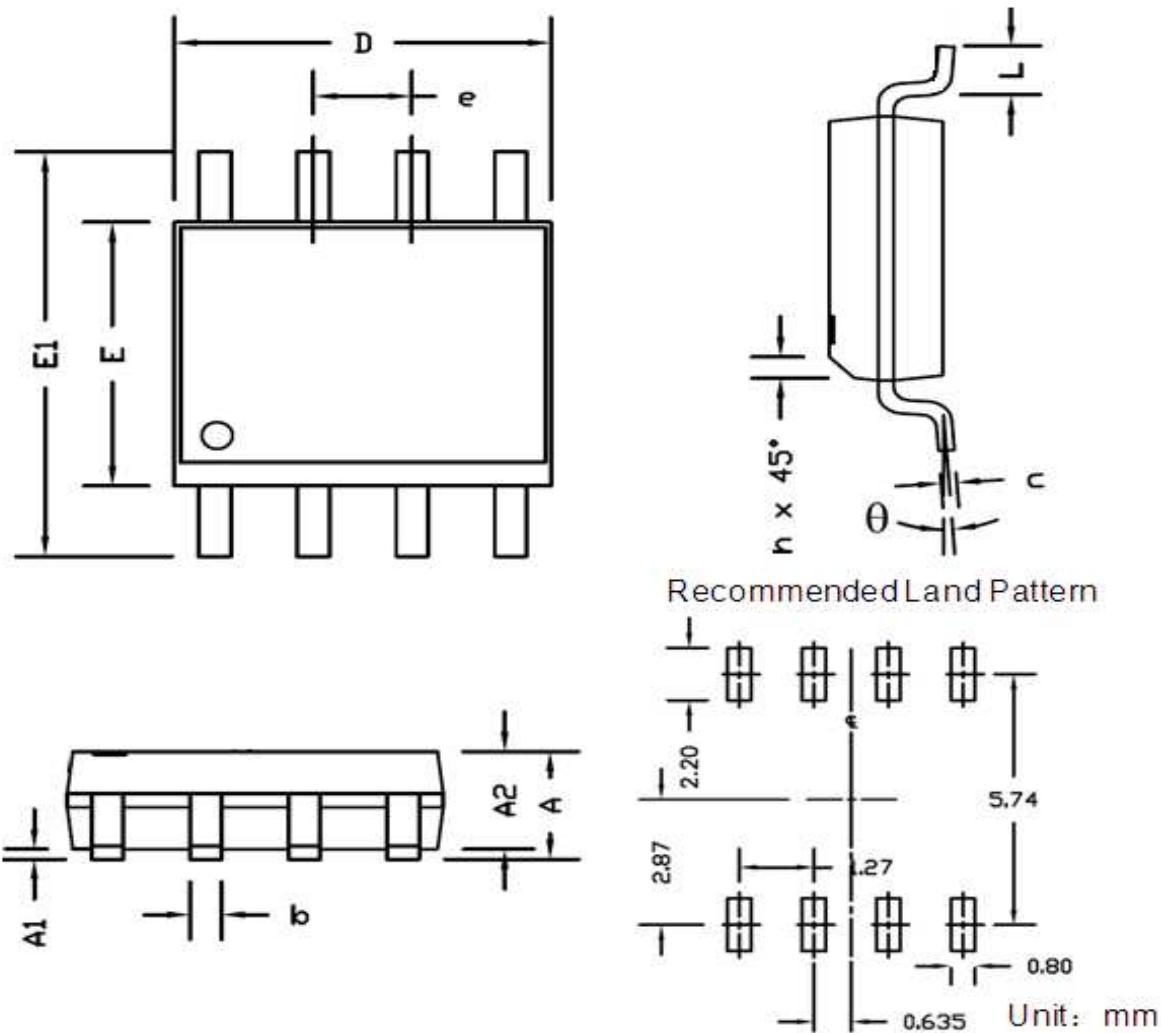


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: SOP-8


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.35	1.75	0.053	0.069
A1	0.10	0.25	0.004	0.010
A2	1.25	1.65	0.049	0.065
b	0.33	0.51	0.013	0.020
c	0.17	0.25	0.007	0.010
D	4.80	5.00	0.189	0.197
e	1.27 BSC.		0.050 BSC.	
E	3.80	4.00	0.150	0.157
E1	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.020
L	0.40	1.27	0.016	0.050
θ	0°	8°	0°	8°



华润微电子（重庆）有限公司

CRSE120N10L2X

SkyMOS2 N-MOSFET 100, 11.0mΩ, 11A

Revision History

Revison	Date	Major changes
1.0	2019-7-24	Release of formal version.

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.